

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: Divisional of Applic. No. GR 98 P 2661 P D 09/816,923 Applicant Manfred Engelhardt Filing Date of Divisional Group Art Unit August 22, 2003 2826			
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EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>den</i>	A	5,308,793	05/94	Taguchi et al.		
	B	5,612,254	03/97	Mu et al.		
	C	5,966,634	10/99	Inohara et al.		
	D	6,150,272	11/00	Liu et al.		
	E	6,136,682	10/00	Hegde et al.		
	F	6,197,688 B1	03/01	Simpson		
	G	6,221,780 B1	04/01	Greco et al.		
	H	6,251,772 B1	06/01	Brown		
<i>den</i>	I	6,472,304 B2	10/02	Chittipeddi et al.		

FOREIGN PATENT DOCUMENT							
DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	TRANSL. NO	
<i>den</i> J	EP 0 798 778 A2	10/97	Europe				
<i>den</i> K	EP 0 892 428 A2	01/99	Europe				
<i>den</i> L							
<i>den</i> M							
<i>den</i> N							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
<i>den</i>	"A High Performance 3.97 μ m ² CMOS SRAM Technology Using Self-Aligned Local Interconnect and Copper Interconnect Metallization" (Woo et al.), 1998 Symposium on VLSI Technology Digest of Technical Papers, pp. 12-13.
<i>den</i>	"A High-Performance Sub-0.25 μ m CMOS Technology with Multiple Thresholds and Copper Interconnects" (Su et al.), 1998 Symposium on VLSI Technology Digest of Technical Papers, pp. 18-19.
EXAMINER _____ DATE CONSIDERED _____	

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>sla</i>	A	US 2002/0098673 A1	07/02	Yeh et al.		
	B	US 2002/0005582 A1	01/02	Nogami et al.		
	C	US 2002/0000665 A1	01/02	Barr et al.		
<i>sla</i>	D	US 2002/0019131 A1	02/02	Ohtsuka et al.		
	E					
	F					
	G					
	H					
	I					

FOREIGN PATENT DOCUMENT							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO	
	J						
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	

EXAMINER <i>Michael Kuyper</i>	DATE CONSIDERED <i>1/09</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.